

Preface

This volume contains the proceedings of the joint IAPR International Workshops on Structural and Syntactic Pattern Recognition (SSPR 2016) and Statistical Techniques in Pattern Recognition (SPR 2016). S+SSPR 2016 is a joint biannual event organized by Technical Committee 1 (Statistical Pattern Recognition Technique) and Technical Committee 2 (Structural and Syntactical Pattern Recognition) of the International Association of Pattern Recognition (IAPR). This year, S+SSPR was held in Mérida, Mexico, from November 29 to December 2, 2016. Merida is the largest city in the Yucatan Peninsula and boasts the second-largest historic center in Mexico after Mexico City.

All submitted full papers were reviewed by at least two members of the Technical Committee. The 51 accepted papers span a wide variety of topics in structural, syntactical, and statistical pattern recognition. Indeed, since its inception, S+SSPR has attracted participants working in a wide variety of fields that make use of statistical, structural or syntactic pattern recognition techniques as well as researchers who make methodological contributions to the field. This has traditionally resulted in a rich mix of papers with applications in image processing, computer vision, bioinformatics, chemo-informatics, machine learning, and document analysis. We are pleased to say that S+SSPR 2016 is no exception to this trend, featuring up-to-date research on areas such as spatio-temporal pattern recognition, texture and shape analysis, semantic segmentation, clustering and classification. S+SSPR also had invited talks by two prominent speakers: Professor Sudeep Sarkar from the University of South Florida and Professor Hamid Krim from North Carolina State University. In addition to parallel oral sessions for SPR and SSPR, there were also joint oral sessions covering topics of interest to both communities and the Pierre Devijver Award Lecture delivered by Professor Mario A.T. Figueiredo.

We would like to thank our sponsors, the British Machine Vision Association (BMVA) and the International Association of Pattern Recognition (IAPR), who helped us to achieve the goals of the conference. We wish to express our appreciation to Springer for publishing this volume. Would also like to thank all the members of the Technical Committee. Without the enthusiasm of the Technical Committee members, their time, and expertise, the reviewing process that has made S+SSPR 2016 possible could never have been completed. Last, but not least, we would like to also thank the authors for submitting their work and making S+SSPR 2016 a success.

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